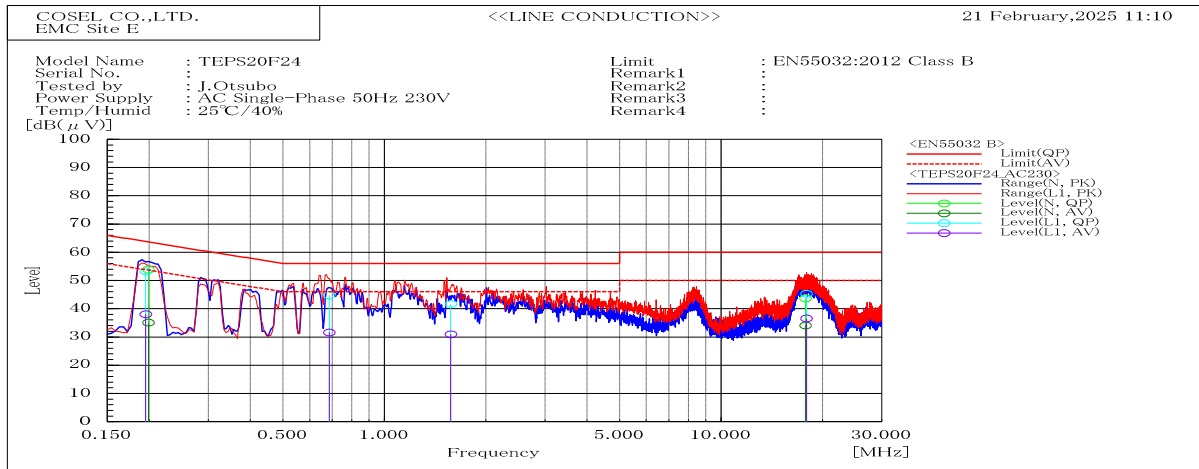
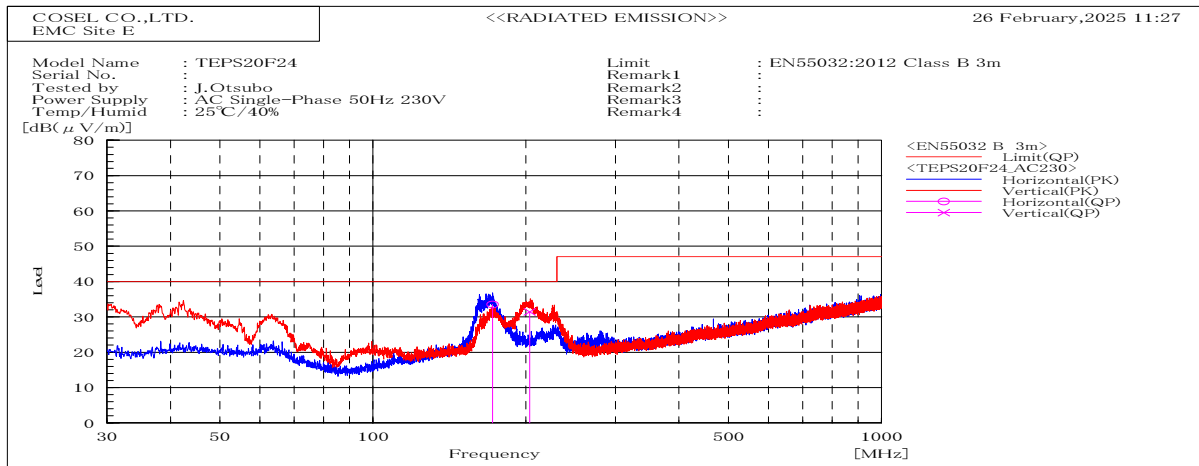


DATA SHEET		Date	24-Mar-25
Model	TEPS20F24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma



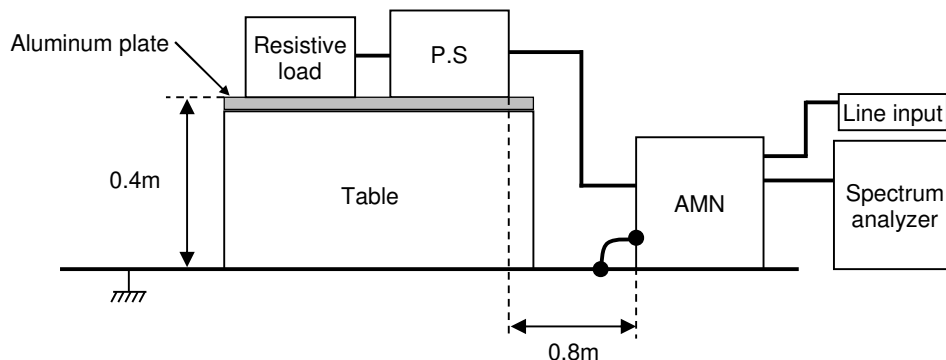
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.196	L1	53.3	38.1	63.8	53.8	10.5	15.7	Pass	
0.686	L1	44.8	31.6	56	46	11.2	14.4	Pass	
1.575	L1	41.7	31	56	46	14.3	15	Pass	
17.932	L1	45.3	36.6	60	50	14.7	13.4	Pass	
0.199	N	53.9	35.1	63.6	53.6	9.7	18.5	Pass	
17.834	N	43.7	34.1	60	50	16.3	15.9	Pass	



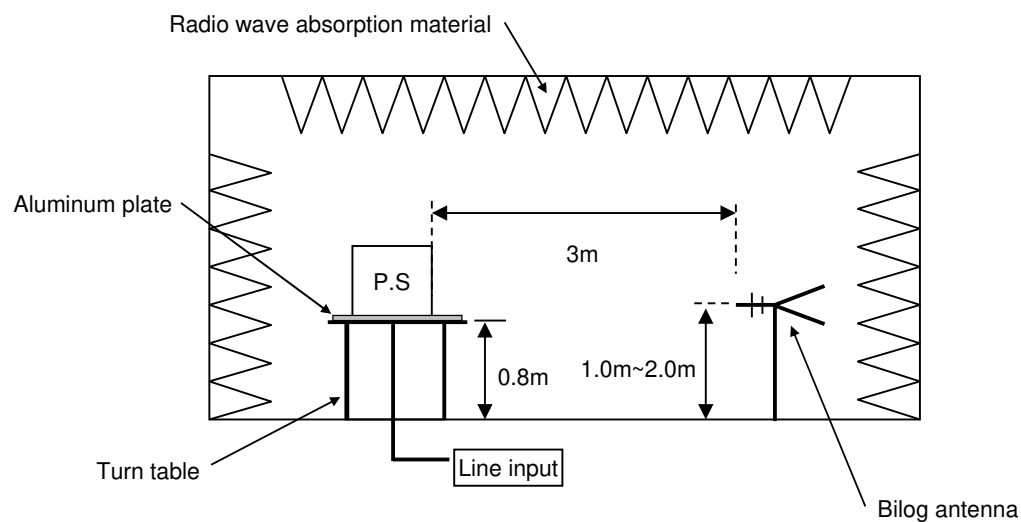
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB				
			QP	QP	QP		cm	deg	
172.013	H	Stable	33.5	40	6.5	Pass	175.8	19.3	
203.266	V	Stable	31.4	40	8.6	Pass	100.2	6.8	

DATA SHEET		Date	24-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma

1. Line conduction



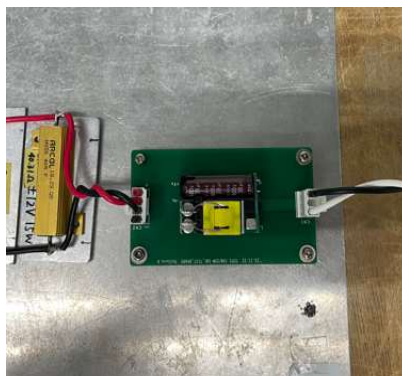
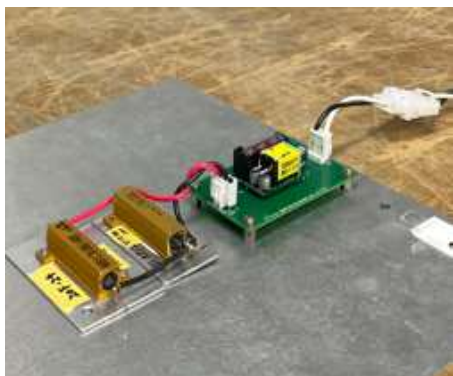
2. Radiated emission



Conditions

Test : EMI
Model Name : TEPS20F24

1.LINE CONDUCTION



2.RADIATED EMISSION

